

Description

These N-Channel enhancement mode power field effect transistors are using split gate trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

- ◆ 100V, 57A, $R_{DS(on),max} = 9.8m\Omega @ V_{GS} = 10V$
- ◆ Improved dv/dt capability
- ◆ Fast switching
- ◆ 100% EAS Guaranteed
- ◆ Green device available

Applications

- ◆ Motor Drives
- ◆ UPS
- ◆ DC-DC Converter

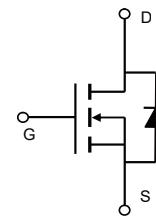
Product Summary

V_{DSS}	100V
$R_{DS(on),max} @ V_{GS}=10V$	9.8mΩ
I_D	57A

Pin Configuration



TO-252



Schematic

Absolute Maximum Ratings

 $T_c = 25^\circ C$ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	100	V
Continuous drain current $(T_c = 25^\circ C)$	I_D	57	A
$(T_c = 100^\circ C)$		39	A
Pulsed drain current ¹⁾	I_{DM}	171	A
Gate-Source voltage	V_{GSS}	± 20	V
Avalanche energy ²⁾	E_{AS}	3.2	mJ
Power Dissipation	P_D	62	W
Storage Temperature Range	T_{STG}	-55 to +150	°C
Operating Junction Temperature Range	T_J	-55 to +150	°C

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	2	°C/W
Thermal Resistance Junction-to-Ambient	$R_{\theta JA}$	50	°C/W

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Reel
VST10N098-T2	TO-252	VST10N098-T2	2500

Electrical Characteristics

 $T_J = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV_{DSS}	$\text{V}_{\text{GS}}=0 \text{ V}, \text{I}_D=250\mu\text{A}$	100	---	---	V
Gate threshold voltage	$\text{V}_{\text{GS}(\text{th})}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	2	3	4	V
Drain-source leakage current	I_{DSS}	$\text{V}_{\text{DS}}=100 \text{ V}, \text{V}_{\text{GS}}=0 \text{ V}$	---	---	1	μA
Gate leakage current, Forward	I_{GSSF}	$\text{V}_{\text{GS}}=20 \text{ V}, \text{V}_{\text{DS}}=0 \text{ V}$	---	---	100	nA
Gate leakage current, Reverse	I_{GSSR}	$\text{V}_{\text{GS}}=-20 \text{ V}, \text{V}_{\text{DS}}=0 \text{ V}$	---	---	-100	nA
Drain-source on-state resistance	$\text{R}_{\text{DS}(\text{on})}$	$\text{V}_{\text{GS}}=10 \text{ V}, \text{I}_D=20 \text{ A}$	---	7.8	9.8	$\text{m}\Omega$
Dynamic characteristics						
Input capacitance	C_{iss}	$\text{V}_{\text{DS}}=50 \text{ V}, \text{V}_{\text{GS}}=0 \text{ V},$ $F=1\text{MHz}$	---	2423	---	pF
Output capacitance	C_{oss}		---	289	---	
Reverse transfer capacitance	C_{rss}		---	12.5	---	
Turn-on delay time	$t_{\text{d}(\text{on})}$	$\text{V}_{\text{DD}}=50\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{I}_D=20\text{A}$ $R_G=3.3\Omega$	---	7.7	---	ns
Rise time	t_r		---	3.9	---	
Turn-off delay time	$t_{\text{d}(\text{off})}$		---	25.8	---	
Fall time	t_f		---	5.6	---	
Gate charge characteristics						
Gate to source charge	Q_{gs}	$\text{V}_{\text{DS}}=50\text{V}, \text{I}_D=20\text{A},$ $\text{V}_{\text{GS}}=10 \text{ V}$	---	5.4	---	nC
Gate to drain charge	Q_{gd}		---	5.1	---	
Gate charge total	Q_g		---	42	---	
Drain-Source diode characteristics and Maximum Ratings						
Continuous Source Current	I_s		---	---	51	A
Pulsed Source Current ³⁾	I_{SM}		---	---	153	A
Diode Forward Voltage	V_{SD}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_s=20\text{A}, T_J=25^\circ\text{C}$	---	---	1.2	V
Reverse recovery time	t_{rr}	$I_F=20\text{A}, dI_F/dt=100 \text{ A}/\mu\text{s}$	---	40.1	---	ns
Reverse recovery charge	Q_{rr}		---	162.3	---	nC

Notes:

1: Repetitive Rating: Pulse width limited by maximum junction temperature.

2: $\text{V}_{\text{DD}}=25\text{V}, \text{V}_{\text{GS}}=10\text{V}, L=0.1\text{mH}, I_{\text{AS}}=8\text{A}$, Starting $T_J=25^\circ\text{C}$.

3: Pulse Test: Pulse Width $\leqslant 300 \mu\text{s}$, Duty Cycle $\leqslant 2\%$.

Electrical Characteristics Diagrams

Figure 1. Typ. Output Characteristics

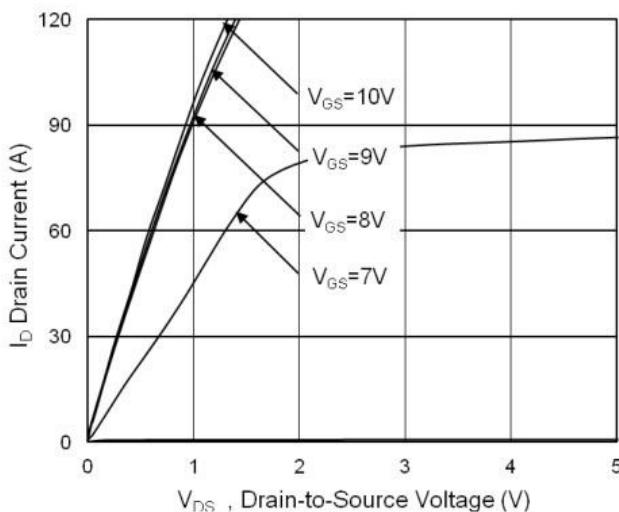


Figure 2. Transfer Characteristics

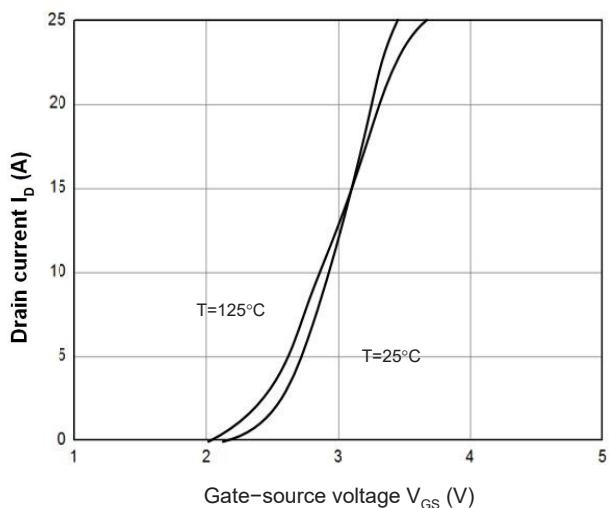


Figure 3. Capacitance Characteristics

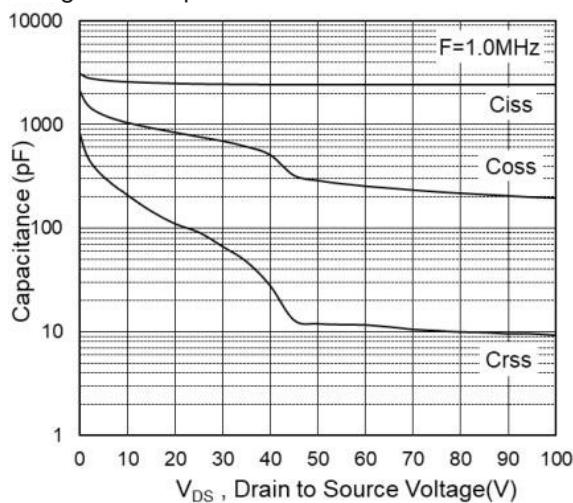


Figure 4. Gate Charge Waveform

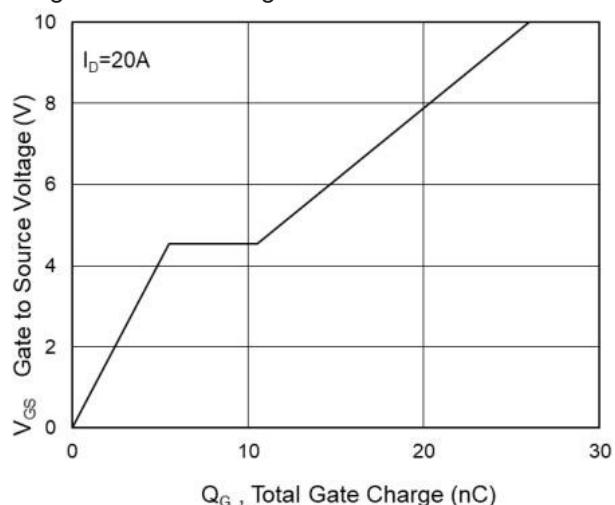


Figure 5. Body-Diode Characteristics

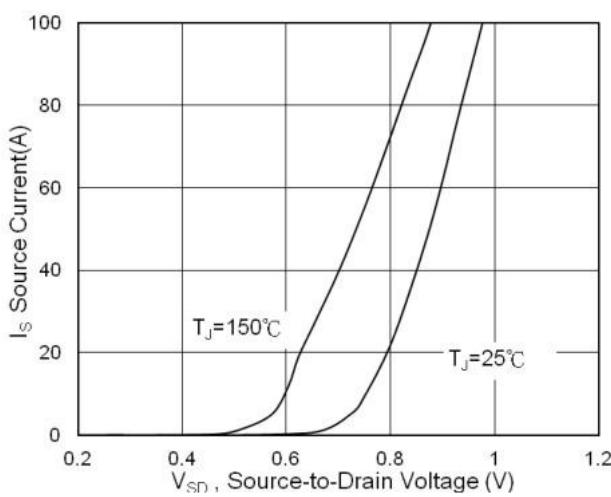


Figure 6. Rdson-Drain Current

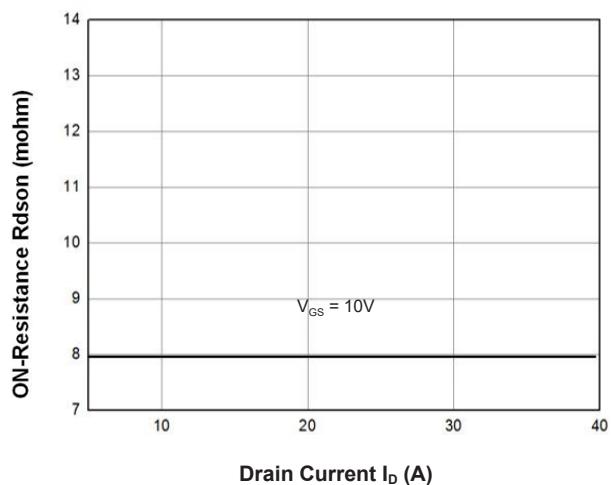


Figure 7. Rdson-Junction Temperature

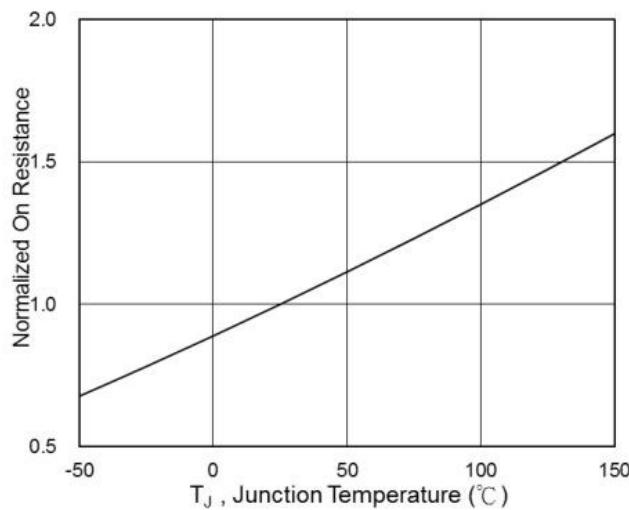


Figure 8. $V_{GS(th)}$ -Junction Temperature

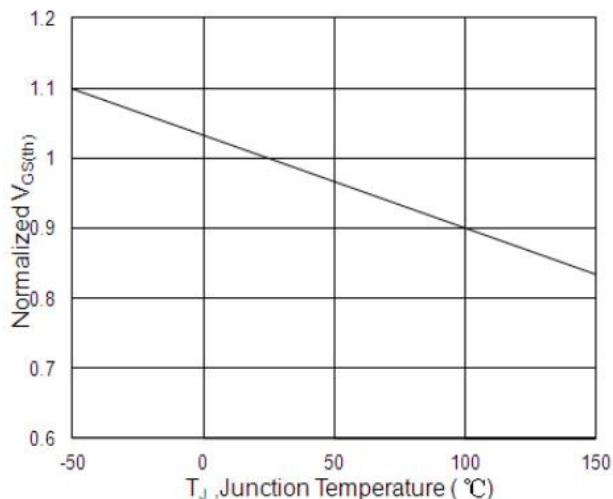


Figure 9. On-Resistance vs. Gate-to-Source voltage

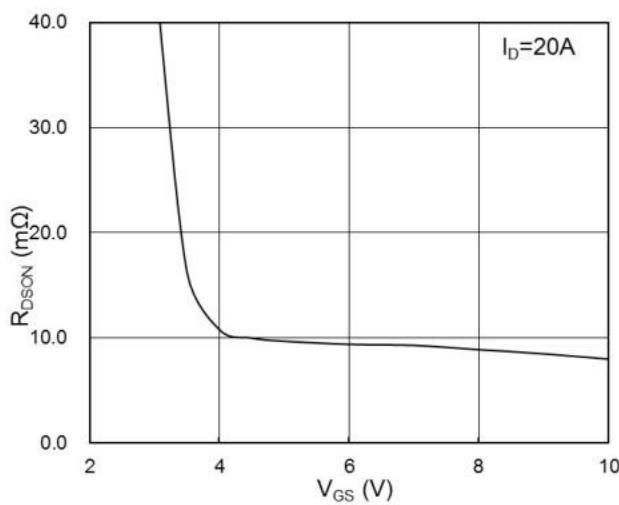


Figure 10: Safe Operating Area

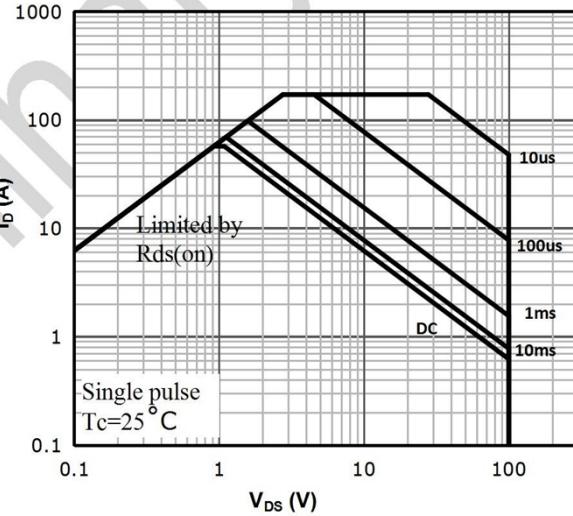
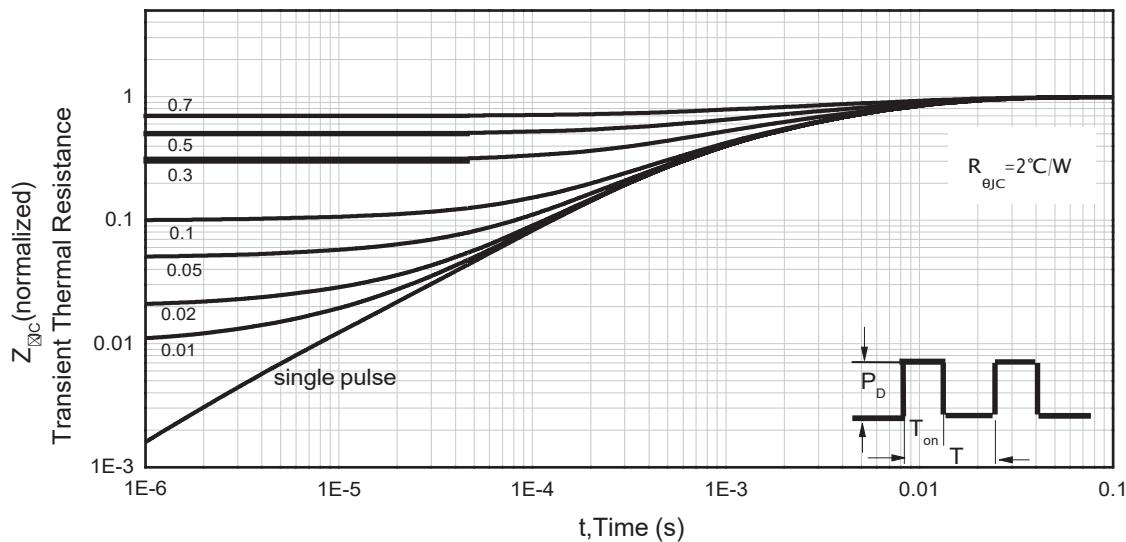
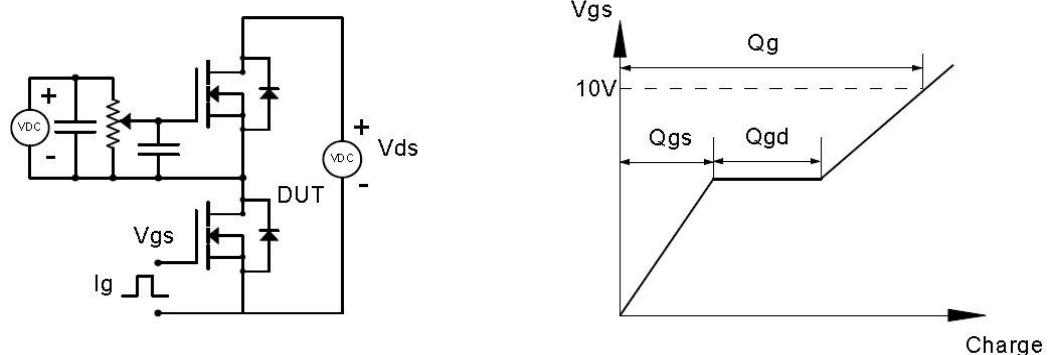


Figure 11. Normalized Maximum Transient Thermal Impedance (R_{thJC})

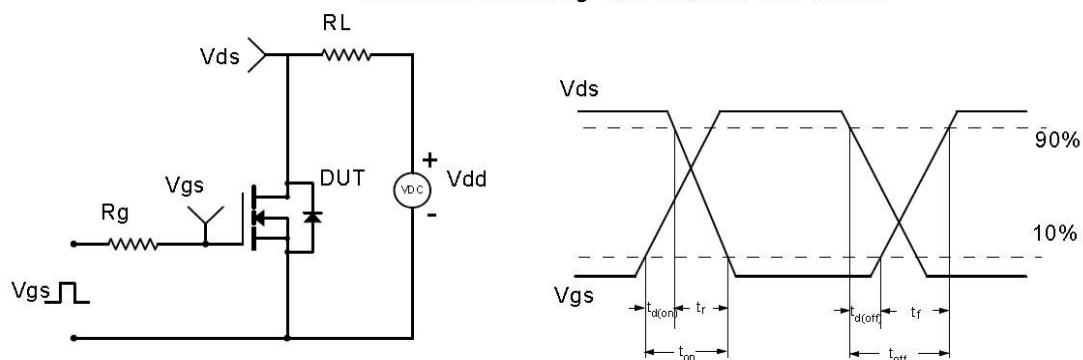


Test Circuit & Waveform

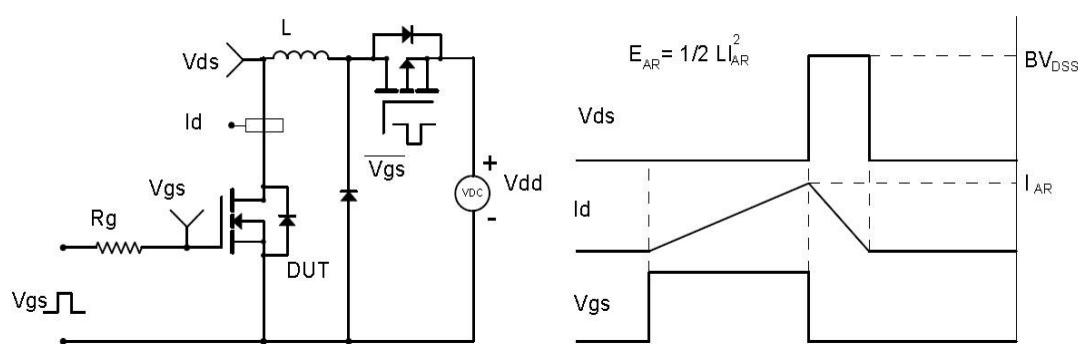
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

